

OptiMOS[™] Small-Signal-Transistor

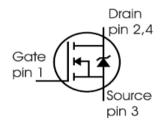
Features

- N-channel
- Enhancement mode
- Logic Level (4.5V rated)
- Avalanche rated
- Qualified according to AEC Q101
- 100% lead-free; RoHS compliant
- Halogen-free according to IEC61249-2-21



Product Summary

V _{DS}	100	٧	
$R_{\rm DS(on),max}$ $V_{\rm GS}$ =10 V		0.23	Ω
	V _{GS} =4.5 V	0.27	
I _D	1.8	Α	





Туре	Package	Tape and Reel	Marking	Halogen-Free	Packing
BSP372N	SOT223	H6327: 1000 pcs/ reel	BSP372N	Yes	Non dry

Maximum ratings, at T_i =25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Continuous drain current	ID	T _A =25 °C	1.8	А
		T _A =70 °C	1.5	
Pulsed drain current	I _{D,pulse}	T _A =25 °C	7.2	
Avalanche energy, single pulse	E _{AS}	$I_{\rm D} = 1.8 \; {\rm A}, \; R_{\rm GS} = 25 \; {\rm \Omega}$	33	mJ
Reverse diode dv/dt	dv/dt	I _D =1.8 A, V _{DS} =80 V, d <i>i</i> /d <i>t</i> =200 A/μs, T _{j,max} =150 °C	6	kV/µs
Gate source voltage	V_{GS}		±20	V
Power dissipation ¹⁾	P _{tot}	T _A =25 °C	1.8	W
Operating and storage temperature	$T_{\rm j}, T_{\rm stg}$		-55 150	°C
ESD Class		JESD22-A114 -HBM	0 (<250V)	
Soldering Temperature			260 °C	
IEC climatic category; DIN IEC 68-1			55/150/56	



Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	
Thermal characteristics						
Thermal resistance junction - soldering point	R_{thJS}		-	-	25	K/W
Thermal resistance	R_{thJA}	minimal footprint	-	-	110	
junction - ambient		6 cm ² cooling area ¹⁾	-	-	70	1

Electrical characteristics, at T_j =25 °C, unless otherwise specified

Static characteristics

Drain-source breakdown voltage	$V_{(BR)DSS}$	V _{GS} =0 V, I _D =250 μA	100	-	-	V
Gate threshold voltage	$V_{\rm GS(th)}$	$V_{\rm DS}$ =Vgs V, $I_{\rm D}$ =218 μ A	0.8	1.4	1.80	
Drain-source leakage current	I _{DSS}	$V_{\rm DS}$ =100 V, $V_{\rm GS}$ =0 V, $T_{\rm j}$ =25 °C	1	1	0.1	μΑ
		V _{DS} =100 V, V _{GS} =0 V, T _j =150 °C	-	-	10	
Gate-source leakage current	I _{GSS}	V _{GS} =20 V, V _{DS} =0 V	-	-	10	nA
Gate-source on-state resistance	R _{DS(on)}	V _{GS} =10 V, I _D =1.8 A	-	153	230	mΩ
		V _{GS} =4.5 V, I _D =1.7 A	-	172	270	
Transconductance	g_{fs}	$ V_{\rm DS} > 2 I_{\rm D} R_{\rm DS(on)max},$ $I_{\rm D} = 1.5~{\rm A}$		5.1	-	s

 $^{^{1)}}$ Device on 40mm x 40mm x 1.5mm epoxy PCB FR4 with 6cm² (one layer, 70 μ m thick) copper area for drain connection. PCB is vertical in still air.



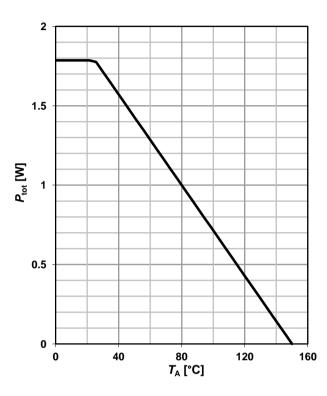
Parameter	Symbol	Symbol Conditions	Values			Unit
			min.	typ.	max.	
Dynamic characteristics						
Input capacitance	Ciss		-	247	329	pF
Output capacitance	Coss	V_{GS} =0 V, V_{DS} =25 V, f =1 MHz	-	40	54	
Reverse transfer capacitance	C _{rss}	1	-	19	28	
Turn-on delay time	$t_{d(on)}$		-	5.1	7.7	ns
Rise time	t _r	V _{DD} =50 V, V _{GS} =10 V,	-	6.7	10.1	
Turn-off delay time	$t_{d(off)}$	$I_{\rm D}$ =1.8 A, $R_{\rm G,ext}$ =6 Ω	-	47.3	71.0	
Fall time	t_{f}]	-	18	27	
Gate Charge Characteristics						_
Gate to source charge	Q _{gs}		-	0.6	0.9	nC
Gate to drain charge	Q_{gd}	$V_{\rm DD}$ =50 V, $I_{\rm D}$ =1.8 A, $V_{\rm GS}$ =0 to 10 V	1	3.0	4.5	
Gate charge total	Qg		-	9.5	14.3	
Gate plateau voltage	V _{plateau}		-	2.3	-	V
Reverse Diode						
Diode continous forward current	Is	T _25 °C	_	-	1.8	А
Diode pulse current	I _{S,pulse}	- T _A =25 °C	-	-	7.2	
Diode forward voltage	V _{SD}	V _{GS} =0 V, I _F =1.8 A, T _j =25 °C	-	0.82	1.1	V
Reverse recovery time	t _{rr}	V _R =50 V, I _F =1.8 A,	-	38	57	ns
Reverse recovery charge	Q _{rr}	$di_F/dt=100 \text{ A/}\mu\text{s}$	-	51.5	77.3	nC

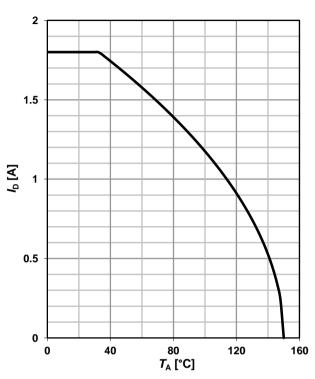


1 Power dissipation

$P_{\text{tot}} = f(T_A)$

2 Drain current





3 Safe operating area

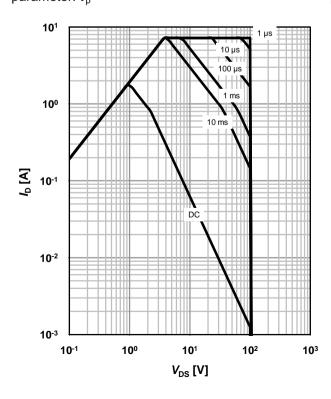
 $I_D=f(V_{DS}); T_A=25 \text{ °C}; D=0$

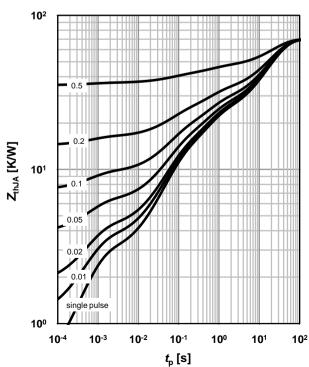
parameter: t_p

4 Max. transient thermal impedance

 $Z_{\text{thJA}} = f(t_p)$

parameter: $D=t_p/T$



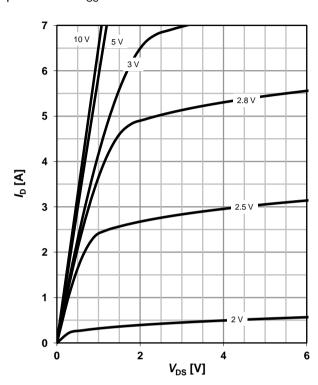




5 Typ. output characteristics

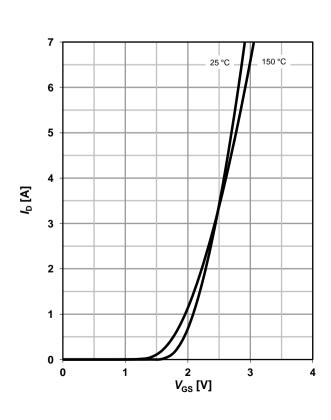
 $I_D=f(V_{DS}); T_j=25 °C$

parameter: V_{GS}



7 Typ. transfer characteristics

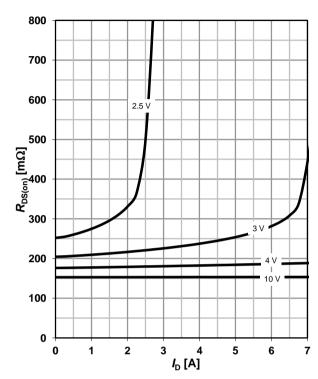
 $I_{D}=f(V_{GS}); |V_{DS}|>2|I_{D}|R_{DS(on)max}$



6 Typ. drain-source on resistance

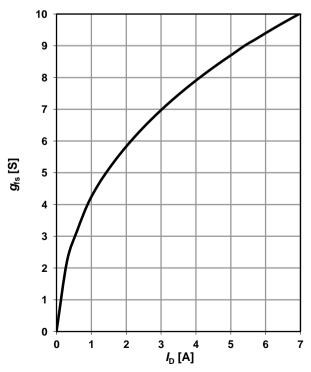
 $R_{DS(on)}=f(I_D); T_j=25 \text{ °C}$

parameter: V_{GS}



8 Typ. forward transconductance

 g_{fs} =f(I_D); T_j =25 °C





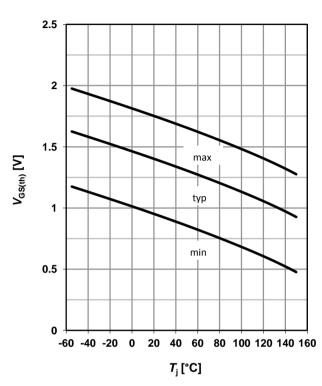
9 Drain-source on-state resistance

 $R_{DS(on)} = f(T_i); I_D = 1.8 A; V_{GS} = 10 V$

500 400 200 100 -60 -40 -20 0 20 40 60 80 100 120 140 160 T_j [°C]

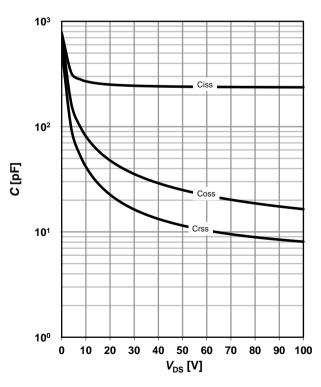
10 Typ. gate threshold voltage

 $V_{\text{GS(th)}}$ =f(T_{j}); V_{DS} = V_{GS} ; I_{D} =218 μ A parameter: I_{D}



11 Typ. capacitances

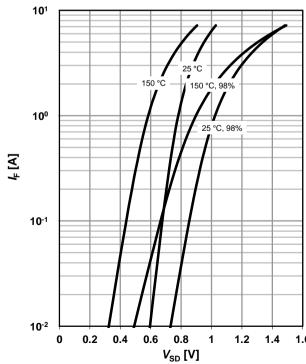
 $C=f(V_{DS}); V_{GS}=0 V; f=1 MHz; T_i=25$ °C



12 Forward characteristics of reverse diode

 $I_{\mathsf{F}} = \mathsf{f}(V_{\mathsf{SD}})$

parameter: T_i

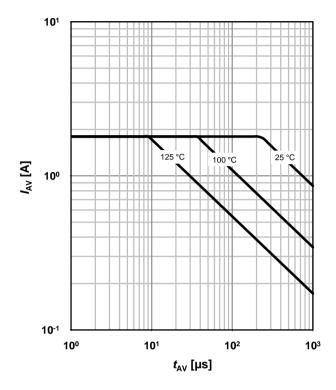




13 Avalanche characteristics

 $I_{AS}=f(t_{AV}); R_{GS}=25 \Omega$

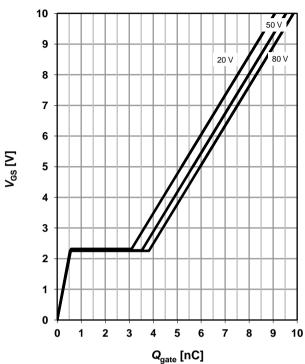
parameter: $T_{j(start)}$



14 Typ. gate charge

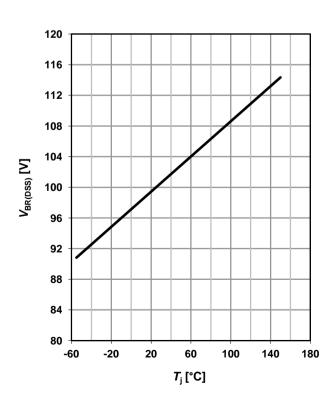
 V_{GS} =f(Q_{gate}); I_D =1.8 A pulsed

parameter: $V_{\rm DD}$

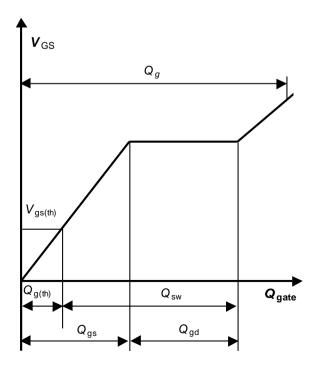


15 Drain-source breakdown voltage

 $V_{BR(DSS)}=f(T_j); I_D=250 \mu A$



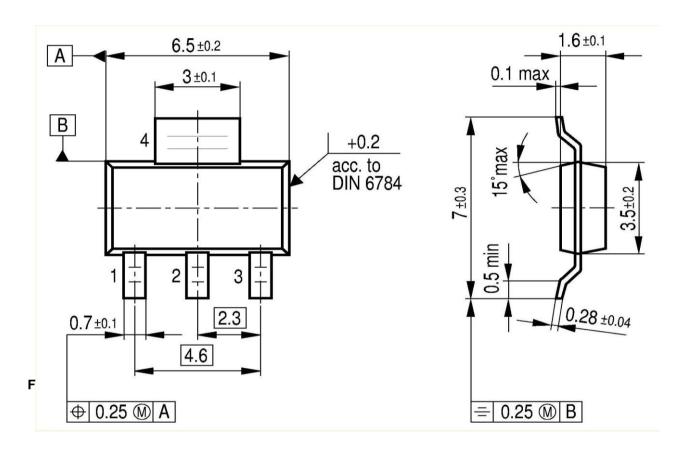
16 Gate charge waveforms

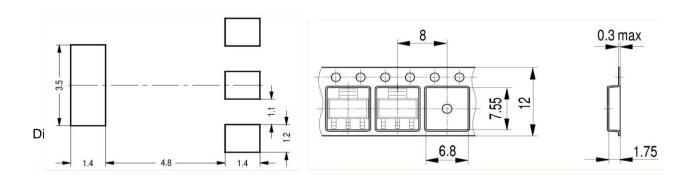




SOT223

Package Outline:







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